



XAFS

Hands on course

DESY, Hamburg, Germany

03 – 07 September 2018

XAFS hands on course

Sample preparation, measurements, data evaluation

X-Ray Absorption Fine Structure (XAFS) Spectroscopy is an important analytical tool at synchrotron radiation facilities. It can reveal important information on the local atomic structure and on the chemical valence of the absorbing atom in solids, liquids, and gases. Due to the high versatility, this method finds applications in physics, chemistry, biology, material, environmental and earth sciences, and even in the study of cultural heritage.

This introductory XAFS course is aimed at new-comers from academia and industry with little or no prior experience with XAFS. Participants will gain theoretical and practical knowledge to judge the applicability of XAFS spectroscopy for their specific scientific problem, and to perform experiments and evaluate the data on their own.

The registration fee is 100 € per person, and a student reduction is available on request. The number of participants is limited to 16, thus early registration is recommended.

Workshop organiser

Wolfgang Caliebe (DESY)

Edmund Welter (DESY)

Tentative list of instructors

Bruce Ravel (APS, XAFS data evaluation)

Mathias Bauer (Uni Paderborn, in-situ experiments)

Jan-Dierck Grunwaldt (KIT)

Ronald Frahm (Uni Wuppertal, Fast scanning EXAFS)

Wolfgang Caliebe (DESY)

Edmund Welter (DESY)

Vadim Murzin (Uni-Wuppertal)

Ruidy Nemausat (DESY)

Alexandre Kalinko (Uni-Paderborn)

Topics:

- Basic EXAFS theory
- Sample preparation
- Measurement techniques
- Hands on experiments
- Data evaluation



For information about registration please visit:

<https://indico.desy.de/indico/event/21097/overview>

E-mail contact: xafs-course@desy.de